

USPTO and EPO Fifth Annual CPC Meeting with National Offices in Geneva, Switzerland

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The 5th CPC Annual Meeting with National Offices, organized by the USPTO and EPO, was held on Tuesday, February 6, 2018, at WIPO (World Intellectual Property Organization) in Geneva, Switzerland, along the margins of the IPC Union Committee of Experts (IPC CE50) meeting.

The meeting had the most participation of national offices, with 26 Offices and about 45 representative from the various Offices.

Christopher Kim, Director of Classification Quality and International Coordination (CQIC); and Dimple Bodawala, International Patent Classifier, CQIC, and LaChelle Carpenter-Parker, Management & Program Analyst (IOA), represented OIPC and USPTO at the annual meeting to provide CPC information and presentations to the national offices. Christopher Kim chaired the meeting, running the meeting with presentations of many Offices. Dimple Bodawala presented the CPC updates. LaChelle organized the whole meeting, handling the coordination with other Offices and WIPO, registration of participants and final



evaluations. As a co-owner of the CPC system, the USPTO was responsible for organizing the 5th Annual Meeting.

The primary objective of the 5th CPC Annual Meeting with National Offices was to provide the latest status on the CPC system (such as CPC participating offices, CPC products, ongoing CPC projects etc.), the recent developments of the CPC system (such as new Web services, search features and combination sets), and the future IT developments of the CPC system (CPC-INTL, CPC CE).

Another objective of the annual meeting was to discuss updates on CPC implementation at the National Offices who are using CPC to classify and search patent documents. As of January 2018, over 50 million documents from all around the world are classified in CPC.

Additional information about the 5th USPTO - EPO CPC Annual Meeting with National Offices can be found at the CPC bilateral website: <http://www.cooperativepatentclassification.org/index.html>.

